

Search Notes

Application/Control No.

10/764,481

Examiner

Mark A. Mais

Applicant(s)/Patent under
Reexamination

HIYAMA ET AL.

Art Unit

2616

SEARCHED

Class	Subclass	Date	Examiner
370	310 328 329	6/16/2007	MAM
	331 338 351		
	352 353 389		
	392 401 469		
	474 475 476		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See Inventorship Search	6/16/2007	MAM
See Attached Electronic Search	6/16/2007	MAM